

1756

PATENT APPLICATION

Applicant: Toshiaki MOTONAGA et al.

Title: HALFTONE PHASE SHIFTING PHOTOMASK AND BLANKS FOR
 HALFTONE PHASE SHIFTING PHOTOMASK THEREFOR AND A
 METHOD FOR FORMING PATTERN BY USING THE HALFTONE
 PHASE SHIFTING PHOTOMASK

Serial No.: 09/825 578 Group: 1756

Confirmation No.: 9940

Filed : April 3, 2001 Examiner: S. Rosasco

International Application No.: N/A

International Filing Date : N/A

Atty. Docket No.: OPS Case 529

Commissioner for Patents
 P.O. Box 1450
 Alexandria, VA 22313-1450

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FIRST CLASS MAILING CERTIFICATE

Sir:

I hereby certify that this correspondence is being deposited with the United States Postal Service under 37 CFR 1.8 as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450, Alexandria, VA 22313-1450, on August 27, 2003.


 Liane L. Churney

LLC/jp

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Correspondence: Information Disclosure Statement dated August 27, 2003
 Copy of Search Report issued June 25, 2003 in European Application No. 01108402.7
 Form PTO-1449 and one copy of each listed reference
 Postal Card

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9/5/03
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PATENT APPLICATION



IN THE U.S. PATENT AND TRADEMARK OFFICE

August 27, 2003

Applicant(s): Toshiaki MOTONAGA et al.

For: HALFTONE PHASE SHIFTING PHOTOMASK AND BLANKS FOR
HALFTONE PHASE SHIFTING PHOTOMASK THEREFOR AND A METHOD
FOR FORMING PATTERN BY USING THE HALFTONE PHASE
SHIFTING PHOTOMASK

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INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(c)(1) and 1.98, enclosed is the Search Report issued in the European application corresponding to the instant application, Form PTO-1449, and the references cited therein.

The undersigned hereby certifies under Rule 1.97(e)(1) that each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

Respectfully submitted,

Liane L. Churney

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INFORMATION DISCLOSURE CITATION	Applicant: Toshiaki MOTONAGA et al. Ser.No. : 09/825 578 Filed : April 3, 2001 Conf. No.: 9940 Atty.Ref.: OPS Case 529 Group : 1756
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U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Date	Name	Class	Sub Class	Filing Date
	AA 5 629 115	05/1997	Kawano et al.			
	AB 5 907 393	05/1999	Kawano et al.			
	AC 5 916 712	06/1999	Miyashita et al.			
	AD 5 938 897	08/1999	Isao et al.			
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Sub Class	Translation Yes	Translation No
	AL JP 09-244212	09/1997	Japan			With English translation and English-language Abstract.	
	AM						
	AN						
	AO						
	AP						

OTHER DOCUMENTS (Including Author, Title, Date, Pages, Etc.)

AR	
AS	

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.